

^{ON Semiconductor®} FGA25N120ANTDTU 1200 V, 25 A NPT Trench IGBT

Features

- NPT Trench Technology, Positive Temperature Coefficient
- Low Saturation Voltage: $V_{CE(sat), typ}$ = 2.0 V @ I_C = 25 A and T_C = 25°C
- Low Switching Loss: E_{off, typ} = 0.96 mJ @ I_C = 25 A and T_C = 25°C
- Extremely Enhanced Avalanche Capability

Applications

Induction Heating, Microwave Oven



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Using ON Semiconductor's proprietary trench design and

advanced NPT technology, the 1200V NPT IGBT offers

superior conduction and switching performances, high avalanche ruggedness and easy parallel operation. This

device is well suited for the reso-nant or soft switching application such as induction heating, microwave oven.

Description

Absolute Maximum Ratings

Symbol	Description		Ratings	Unit
V _{CES}	Collector-Emitter Voltage		1200	V
V _{GES}	Gate-Emitter Voltage		± 20	V
1	Collector Current	@ T _C = 25°C	50	А
I _C	Collector Current	@ T _C = 100°C	25	А
I _{CM (1)}	Pulsed Collector Current		90	A
I _F	Diode Continuous Forward Current	@ T _C = 25°C	50	А
	Diode Continuous Forward Current	@ T _C = 100°C	25	A
I _{FM}	Diode Maximum Forward Current		150	A
D	Maximum Power Dissipation	@ T _C = 25°C	312	W
P _D	Maximum Power Dissipation	@ T _C = 100°C	125	W
TJ	Operating Junction Temperature		-55 to +150	°C
T _{stg}	Storage Temperature Range		-55 to +150	٥C
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

Notes:

(1) Repetitive rating: Pulse width limited by max. junction temperature

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JC}(IGBT)$	Thermal Resistance, Junction-to-Case		0.4	°C/W
$R_{\theta JC}(DIODE)$	Thermal Resistance, Junction-to-Case		2.0	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

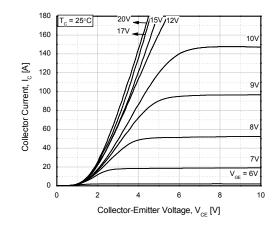
Part Number		Top Mark	Package	Packing Method Tube	Reel Size	Tape Width		Quantity 30	
FGA25N120ANTDTU-F109		FGA25N120ANTDTU	TO-3PN		N/A				
		I							
	I	eristics of the IC	-				1		
Symbol	Pa	arameter	Test Conditions		Min.	Тур.	Мах	. Unit	
Off Charac	teristics								
I _{CES}	Collector Cut-Of	f Current	$V_{CE} = V_{CE}$	_S , V _{GE} = 0 V			3	mA	
I _{GES}	G-E Leakage Cu	ırrent	V _{GE} = V _{GE}	$V_{GE} = V_{GES}, V_{CE} = 0 V$			± 250	nA	
On Charac	teristics								
V _{GE(th)}	G-E Threshold Voltage		I _C = 25 m	I _C = 25 mA, V _{CE} = V _{GE}		5.5	7.5	V	
()			-	V _{GE} = 15 V		2.0		V	
V _{CE(sat)}	Collector to Emitter Saturation Voltage		$I_{C} = 25 \text{ A}, V_{GE} = 15 \text{ V},$ $T_{C} = 125^{\circ}\text{C}$			2.15		V	
			I _C = 50 A, V _{GE} = 15 V			2.65		V	
Dynamic C	haracteristics								
C _{ies}	Input Capacitand	æ	V = 20 V	V _{CE} = 30 V, V _{GE} = 0 V,		3700		pF	
C _{oes}	Output Capacita		f = 1 MHz			130		pF	
C _{res}	Reverse Transfe	r Capacitance				80		pF	
<u>Curitahina</u>	Chana stanistica		-		I				
t _{d(on)}	Characteristics Turn-On Delay T	ïme				50		ns	
t _r	Rise Time		_			60		ns	
t _{d(off)}	Turn-Off Delay T	ïme		V _{CC} = 600 V, I _C = 25 A, R _G = 10 Ω, V _{GE} = 15 V,		190		ns	
t _f	Fall Time		V _{CC} = 600 R _C = 10 Ω			100		ns	
E _{on}	Turn-On Switchi	ng Loss	Inductive L	_oad, T _C = 25°C		4.1		mJ	
E _{off}	Turn-Off Switchin	-	-			0.96		mJ	
E _{ts}	Total Switching L	0	-			5.06		mJ	
t _{d(on)}	Turn-On Delay T					50		ns	
t _r	Rise Time		-			60		ns	
t _{d(off)}	Turn-Off Delay T	ïme	$V_{00} = 600$	V lo = 25 A		200		ns	
t _f	Fall Time		$ V_{CC} = 600 \text{ V, } I_C = 25 \text{ A,} \\ R_G = 10\Omega, V_{GE} = 15 \text{ V,} \\ Inductive Load, T_C = 125^{\circ}\text{C} $		154		ns		
E _{on}	Turn-On Switchi	ng Loss			4.3		mJ		
E _{off}	Turn-Off Switching	-	-			1.5		mJ	
E _{ts}	Total Switching L	OSS	1			5.8		mJ	
Qg	Total Gate Charg	je				200		nC	
Q _{ge}	Gate-Emitter Ch	arge		V, I _C = 25 A,		15		nC	
Q _{gc}	Gate-Collector C	borgo	V _{GE} = 15 V			100		nC	

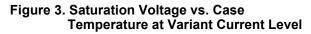
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Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V_{FM}	Diode Forward Voltage	$I_{\rm F} = 25 {\rm A}$	$T_{C} = 25^{\circ}C$		2.0	3.0	v
			T _C = 125°C		2.1		
t _{rr}	Diode Reverse Recovery Time		$T_{C} = 25^{\circ}C$		235	350	ns
		I _F = 25 A	T _C = 125°C		300		
I _{rr}	Diode Peak Reverse Recovery Cur- rent		$T_{C} = 25^{\circ}C$		27	40	A
			T _C = 125°C		31		
Q _{rr}	Diode Reverse Recovery Charge		$T_{C} = 25^{\circ}C$		3130	4700	nC
			T _C = 125°C		4650		

Typical Performance Characteristics

Figure 1. Typical Output Characteristics





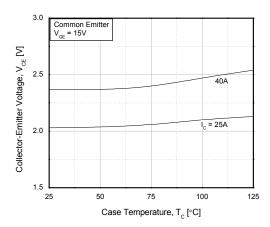


Figure 5. Saturation Voltage vs. V_{GE}

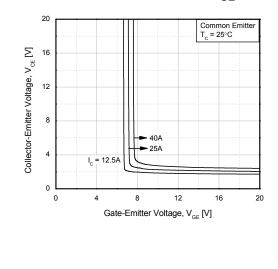


Figure 2. Typical Saturation Voltage Characteristics

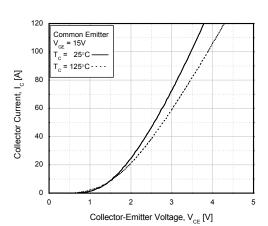


Figure 4. Saturation Voltage vs. V_{GE}

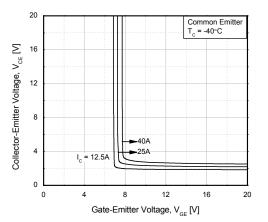
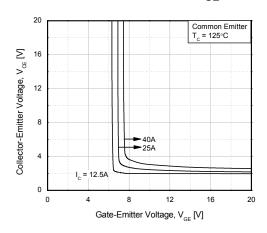
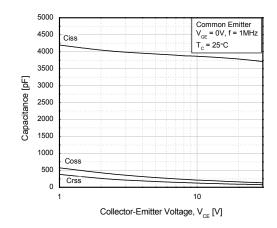


Figure 6. Saturation Voltage vs. V_{GE}

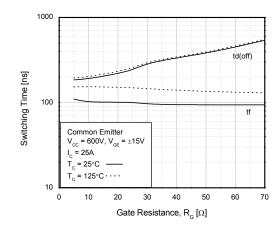


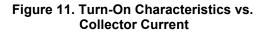
Typical Performance Characteristics (Continued)

Figure 7. Capacitance Characteristics









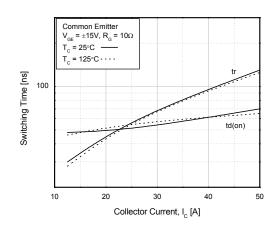


Figure 8. Turn-On Characteristics vs. Gate Resistance

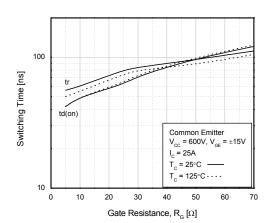


Figure 10. Switching Loss vs. Gate Resistance

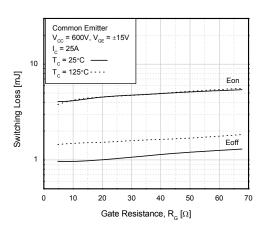
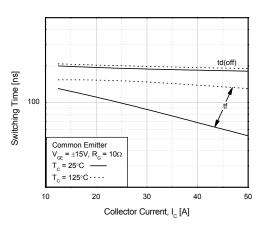
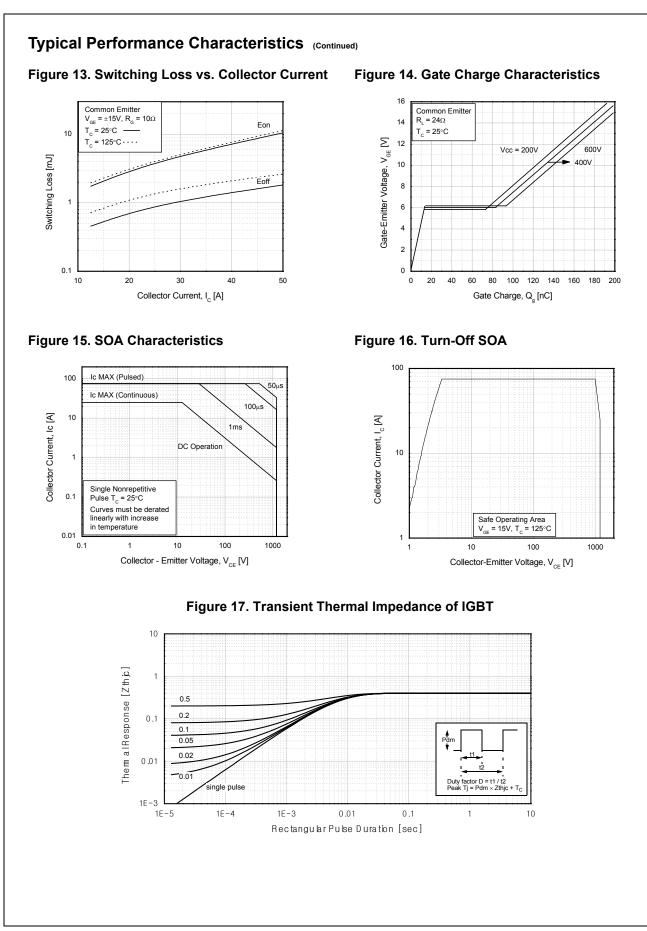


Figure 12. Turn-Off Characteristics vs. Collector Current

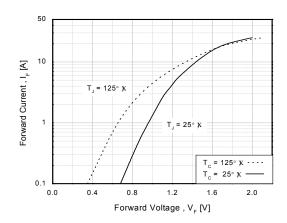




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Typical Performance Characteristics (Continued)

Figure 18. Forward Characteristics



30 $di_F/dt = 200A/\mu s$ 25

 $di_{F}/dt = 100A/\mu s$

Figure 19. Reverse Recovery Current

20

15

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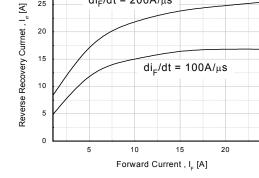


Figure 20. Stored Charge

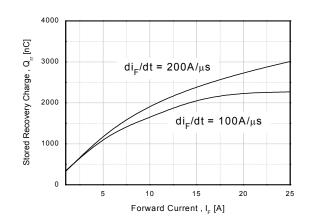
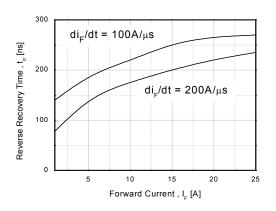
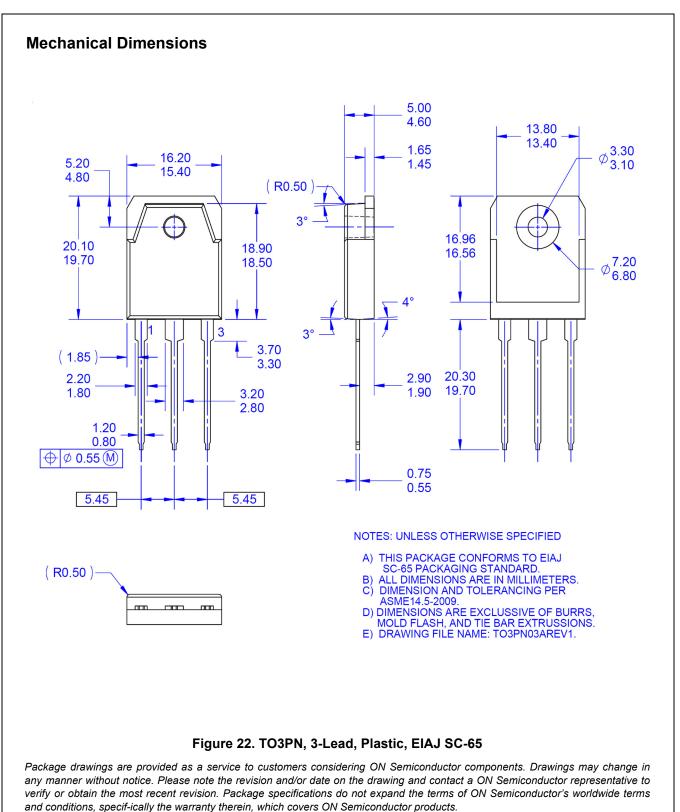


Figure 21. Reverse Recovery Time





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